Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/772,790	SCHERSL, ENDRE MARKOVITS	
Examiner	Art Unit	

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Abigail M. Cotton

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Class	Subclass	Date	Examiner
514	724	2/27/2006	AMC
514	553 558 512	2/27/2006	AMC
514	506 529 546	2/27/2006	AMC
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
				
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Search on Palm	2/28/2006	AMC
EAST (USPAT, US-PGPUB, USOCR, EPO, JPO, DERWENT) - See Search History Report	2/27/2006	AMC
STN (CAPlus, Medline, Embase) - See Search History Report	2/27/2006	AMC
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